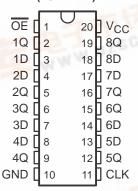
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- EPIC™ (Enhanced-Performance Implanted CMOS) Submicron Process
- Typical V<sub>OLP</sub> (Output Ground Bounce)
  < 0.8 V at V<sub>CC</sub> = 3.3 V, T<sub>A</sub> = 25°C
- Typical V<sub>OHV</sub> (Output V<sub>OH</sub> Undershoot)
  2 V at V<sub>CC</sub> = 3.3 V, T<sub>A</sub> = 25°C
- Power Off Disables Inputs/Outputs, Permitting Live Insertion
- Support Mixed-Mode Signal Operation on All Ports (5-V Input/Output Voltage With 3.3-V V<sub>CC</sub>)
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Package Options Include Plastic Small-Outline (DW), Shrink Small-Outline (DB), and Thin Shrink Small-Outline (PW) Packages, Ceramic Chip Carriers (FK), Ceramic Flat (W) Package, and DIPs (J)

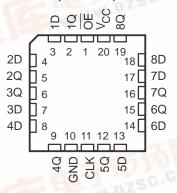
#### description

The SN54LVC374A octal edge-triggered D-type flip-flop is designed for 2.7-V to 3.6-V  $\rm V_{CC}$  operation and the SN74LVC374A octal edge-triggered D-type flip-flop is designed for 1.65-V to 3.6-V  $\rm V_{CC}$  operation.

SN54LVC374A . . . J OR W PACKAGE SN74LVC374A . . . DB, DW, OR PW PACKAGE (TOP VIEW)



SN54LVC374A . . . FK PACKAGE (TOP VIEW)



These devices feature 3-state outputs designed specifically for driving highly capacitive or relatively low-impedance loads. These devices are particularly suitable for implementing buffer registers, input/output (I/O) ports, bidirectional bus drivers, and working registers.

On the positive transition of the clock (CLK) input, the Q outputs are set to the logic levels set up at the data (D) inputs.

A buffered output-enable ( $\overline{OE}$ ) input can be used to place the eight outputs in either a normal logic state (high or low logic levels) or a high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and increased drive provide the capability to drive bus lines without interface or pullup components.

OE does not affect internal operations of the latch. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

Inputs can be driven from either 3.3-V or 5-V devices. This feature allows the use of these devices as translators in a mixed 3.3-V/5-V system environment.



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#### description (continued)

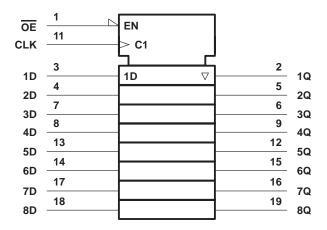
To ensure the high-impedance state during power up or power down,  $\overline{OE}$  should be tied to  $V_{CC}$  through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN54LVC374A is characterized for operation over the full military temperature range of  $-55^{\circ}$ C to  $125^{\circ}$ C. The SN74LVC374A is characterized for operation from  $-40^{\circ}$ C to  $85^{\circ}$ C.

## FUNCTION TABLE (each flip-flop)

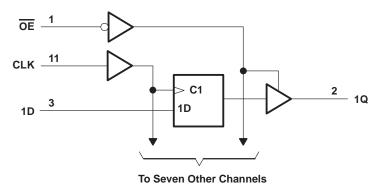
	INPUTS	OUTPUT	
OE	CLK	D	Q
L	1	Н	Н
L	$\uparrow$	L	L
L	H or L	Χ	Q <sub>0</sub>
Н	Χ	Χ	Z

### logic symbol†



 $<sup>\</sup>dagger$  This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

#### logic diagram (positive logic)





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#### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V <sub>CC</sub>	
Voltage range applied to any output in the high-impedance or power-off state, V <sub>O</sub> (see Note 1)	_0.5 \/ to 6.5 \/
Voltage range applied to any output in the high or low state, V <sub>O</sub>	
(see Notes 1 and 2)	$\dots$ -0.5 V to V <sub>CC</sub> + 0.5 V
Input clamp current, I <sub>IK</sub> (V <sub>I</sub> < 0)	
Output clamp current, I <sub>OK</sub> (V <sub>O</sub> < 0)	
Continuous output current, I <sub>O</sub>	
Continuous current through V <sub>CC</sub> or GND	
Package thermal impedance, θ <sub>JA</sub> (see Note 3): DB package	
DW package	
PW package	
Storage temperature range, T <sub>stg</sub>	

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
  - 2. The value of  $V_{\hbox{\scriptsize CC}}$  is provided in the recommended operating conditions table.
  - 3. The package thermal impedance is calculated in accordance with JESD 51.

#### recommended operating conditions (see Note 4)

			SN54LVC374A		SN74L\	SN74LVC374A		
			MIN	MAX	MIN	MAX	UNIT	
\/	Cumply voltage	Operating	2	3.6	1.65	3.6	V	
VCC	Supply voltage	Data retention only	1.5		1.5		ľ	
		V <sub>CC</sub> = 1.65 V to 1.95 V			0.65 × V <sub>CC</sub>			
$V_{IH}$	High-level input voltage	V <sub>CC</sub> = 2.3 V to 2.7 V			1.7		V	
		V <sub>CC</sub> = 2.7 V to 3.6 V	2		2			
		V <sub>CC</sub> = 1.65 V to 1.95 V				0.35 × V <sub>CC</sub>		
$V_{IL}$	Low-level input voltage	V <sub>CC</sub> = 2.3 V to 2.7 V				0.7	V	
		V <sub>CC</sub> = 2.7 V to 3.6 V		0.8		0.8	1	
VI	Input voltage		0	5.5	0	5.5	V	
\/-	Output voltage	High or low state	0	Vcc	0	Vcс	V	
VO	Output voltage	3 state	0	5.5	0	5.5	l v	
		V <sub>CC</sub> = 1.65 V				-4		
la	High lovel output ourrent	V <sub>CC</sub> = 2.3 V				-8	^	
ЮН	High-level output current	V <sub>CC</sub> = 2.7 V		-12		-12	mA	
		VCC = 3 V		-24		-24		
		V <sub>CC</sub> = 1.65 V				4		
1	Low lovel output ourrent	V <sub>CC</sub> = 2.3 V				8	mA	
lOL	Low-level output current	V <sub>CC</sub> = 2.7 V		12		12	mA	
		V <sub>CC</sub> = 3 V		24		24		
Δt/Δν	Input transition rise or fall rate		0	10	0	10	ns/V	
TA	Operating free-air temperature		-55	125	-40	85	°C	

NOTE 4: All unused inputs of the device must be held at V<sub>CC</sub> or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.



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## electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETER	TEST CONDITIONS			SN54	LVC374	Ą	SN74	LVC374	A	UNIT
PARAMETER	LESI CONDITI	ONS	v <sub>CC</sub>	MIN	TYP <sup>†</sup>	MAX	MIN	TYP <sup>†</sup>	MAX	UNII
	100		1.65 V to 3.6 V				V <sub>CC</sub> -0.2			
	ΙΟΗ = –100 μΑ		2.7 V to 3.6 V	V <sub>CC</sub> -0.2						
	I <sub>OH</sub> = -4 mA		1.65 V				1.2			
Voн	$I_{OH} = -8 \text{ mA}$		2.3 V				1.7			V
	I <sub>OH</sub> = -12 mA		2.7 V	2.2			2.2			
	IOH = -12 IIIA		3 V	2.4			2.4			
	I <sub>OH</sub> = -24 mA		3 V	2.2			2.2			
	I <sub>OL</sub> = 100 μA		1.65 V to 3.6 V						0.2	
			2.7 V to 3.6 V			0.2				
\/a:	I <sub>OL</sub> = 4 mA		1.65 V						0.45	V
VOL	I <sub>OL</sub> = 8 mA		2.3 V						0.7	V
	I <sub>OL</sub> = 12 mA		2.7 V			0.4			0.4	
	I <sub>OL</sub> = 24 mA		3 V			0.55			0.55	
lį	$V_{ } = 0 \text{ to } 5.5 \text{ V}$		3.6 V			±5			±5	μΑ
l <sub>off</sub>	V <sub>I</sub> or V <sub>O</sub> = 5.5 V		0						±10	μΑ
loz	$V_0 = 0 \text{ to } 5.5 \text{ V}$		3.6 V			±15			±10	μА
	$V_I = V_{CC}$ or GND		0.014		-	10			10	Δ.
Icc	$3.6 \text{ V} \le \text{V}_{\text{I}} \le 5.5 \text{ V}^{\ddagger}$	IO = 0	3.6 V			10			10	μΑ
ΔICC	One input at V <sub>CC</sub> – 0.6 Other inputs at V <sub>CC</sub> or		2.7 V to 3.6 V			500			500	μΑ
Ci	V <sub>I</sub> = V <sub>CC</sub> or GND		3.3 V		4	12		4		pF
Co	$V_O = V_{CC}$ or GND		3.3 V		5.5	12		5.5		pF

<sup>†</sup> All typical values are at V<sub>CC</sub> = 3.3 V, T<sub>A</sub> = 25°C.

## timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figure 3)

			SN54LV	/C374A		
		V <sub>CC</sub> = 2.7 V		V <sub>CC</sub> = 3.3 V ± 0.3 V		UNIT
		MIN	MAX	MIN	MAX	
fclock	Clock frequency		80		100	MHz
t <sub>W</sub>	Pulse duration, CLK high or low	3.3		3.3		ns
t <sub>su</sub>	Setup time, data before CLK↑	2		2		ns
th	Hold time, data after CLK↑	1.5		1.5		ns

<sup>&</sup>lt;sup>‡</sup> This applies in the disabled state only.

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## timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

		SN74LVC374A								
		V <sub>CC</sub> =		V <sub>CC</sub> =	2.5 V 2 V	VCC =	CC = 2.7 V VCC = 3.3 V ± 0.3 V		3.3 V 3 V	UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
fclock	Clock frequency		†		†		80		100	MHz
t <sub>W</sub>	Pulse duration, CLK high or low	†		†		3.3		3.3		ns
t <sub>su</sub>	Setup time, data before CLK↑	†		†		2		2		ns
th	Hold time, data after CLK↑	†		†		1.5		1.5		ns

<sup>&</sup>lt;sup>†</sup> This information was not available at the time of publication.

## switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figure 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V <sub>CC</sub> =	2.7 V	V <sub>CC</sub> = 3.3 V ± 0.3 V		UNIT
			MIN	MAX	MIN	MAX	
f <sub>max</sub>			80		100		MHz
t <sub>pd</sub>	CLK	Q		9.5	1	8.5	ns
t <sub>en</sub>	ŌĒ	Q	·	9.5	1	8.5	ns
t <sub>dis</sub>	ŌĒ	Q		8	1	7	ns

# switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

			SN74LVC374A								
PARAMETER	FROM (INPUT)	TO (OUTPUT)		V <sub>CC</sub> = 1.8 V ± 0.15 V V <sub>CC</sub> = 2.5 V ± 0.2 V		V <sub>CC</sub> = 2.7 V		V <sub>CC</sub> = 3.3 V ± 0.3 V		UNIT	
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f <sub>max</sub>			†		†		80		100		MHz
t <sub>pd</sub>	CLK	Q	†	†	†	†		8.1	1.5	7	ns
t <sub>en</sub>	ŌĒ	Q	†	†	†	†		8.5	1.5	7.5	ns
t <sub>dis</sub>	ŌĒ	Q	†	†	†	†		7.1	1.5	6.5	ns
t <sub>sk(o)</sub> ‡										1	ns

<sup>†</sup> This information was not available at the time of publication.

### operating characteristics, T<sub>A</sub> = 25°C

PARAMETER			TEST CONDITIONS	V <sub>CC</sub> = 1.8 V ± 0.15 V	V <sub>CC</sub> = 2.5 V ± 0.2 V	V <sub>CC</sub> = 3.3 V ± 0.3 V	UNIT
				TYP	TYP	TYP	
C <sub>pd</sub>	Power dissipation capacitance	Outputs enabled	f = 10 MHz	†	†	54.5	pF
Popa	per flip-flop	flop Outputs disabled		†	†	13.5	pr

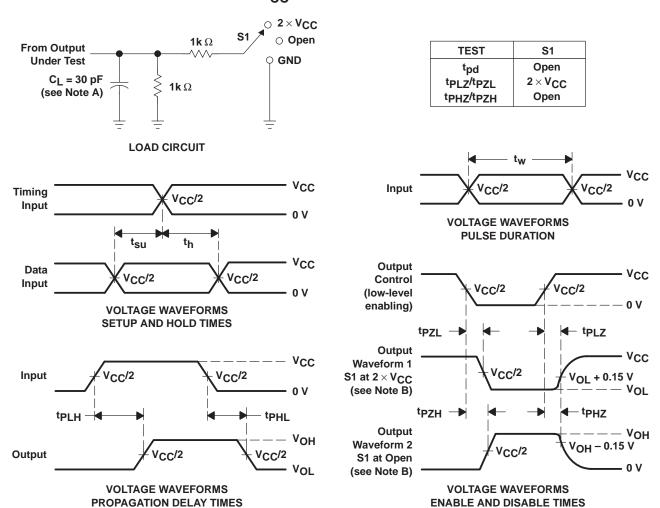
<sup>†</sup> This information was not available at the time of publication.



<sup>‡</sup> Skew between any two outputs of the same package switching in the same direction

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## PARAMETER MEASUREMENT INFORMATION $V_{CC} = 1.8 \text{ V} \pm 0.15 \text{ V}$

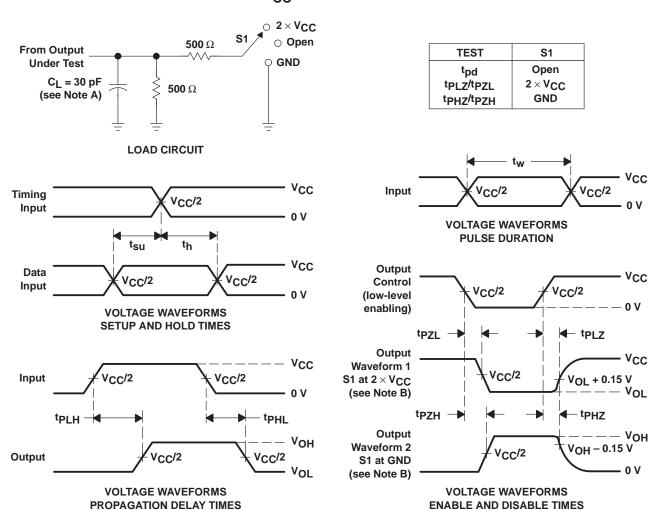


- NOTES: A. C<sub>L</sub> includes probe and jig capacitance.
  - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
  - C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz,  $Z_O = 50 \Omega$ ,  $t_r \leq$  2 ns.  $t_f \leq$  2 ns.
  - D. The outputs are measured one at a time with one transition per measurement.
  - E. tpLz and tpHz are the same as tdis.
  - F. tpzL and tpzH are the same as ten.
  - G. tpLH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms

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## PARAMETER MEASUREMENT INFORMATION $V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$



NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

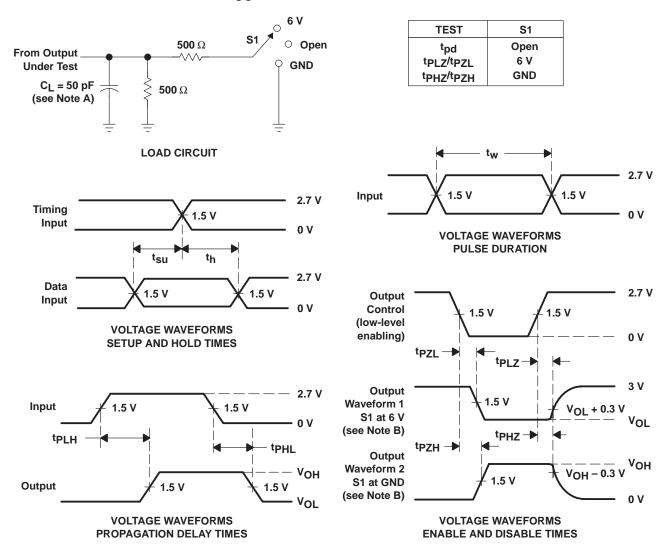
- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR $\leq$ 10 MHz, Z<sub>O</sub> = 50  $\Omega$ ,  $t_r\leq$ 2 ns.  $t_f\leq$ 2 ns.
- D. The outputs are measured one at a time with one transition per measurement.
- E. tpLZ and tpHZ are the same as tdis.
- F. tpzL and tpzH are the same as ten.
- G. tpLH and tpHL are the same as tpd.

Figure 2. Load Circuit and Voltage Waveforms



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## PARAMETER MEASUREMENT INFORMATION $V_{CC}$ = 2.7 V AND 3.3 V $\pm$ 0.3 V



NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz,  $Z_O = 50 \Omega$ ,  $t_f \leq$  2.5 ns.  $t_f \leq$  2.5 ns.
- D. The outputs are measured one at a time with one transition per measurement.
- E. tpl 7 and tpH7 are the same as tdis.
- F.  $t_{PZL}$  and  $t_{PZH}$  are the same as  $t_{en}$ .
- G. tpLH and tpHL are the same as tpd.

Figure 3. Load Circuit and Voltage Waveforms

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